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PATENTIN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: CHUDоба, T. - 1 PCT  
PCT NO. : PCT/DE2003/003556 FILED: OCT. 23, 2003  
PRIORITY : GERMAN NO. 102 49 767.2 FILED: OCT. 24, 2002  
TITLE : TEST TABLE FOR MEASURING LATERAL FORCES AND  
DISPLACEMENTS

INFORMATION DISCLOSURE STATEMENT

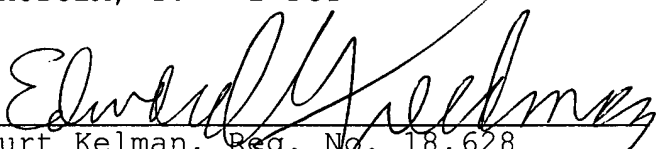
MAILSTOP: PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

S I R :

Applicants are enclosing Form PTO-1449 disclosing the references cited in the International Search Report, copy enclosed. As it is believed that copies of the references cited in the Search Report were forwarded by the International Office, we are not enclosing copies of these references. Since the instant Information Disclosure Statement is being filed concurrently with the application, no official fee is required in connection with the same.

It is respectfully requested that the foregoing Information Disclosure Statement be incorporated into the official file of the concurrently-filed PCT patent application.

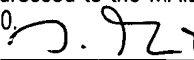
Respectfully submitted,  
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DATE OF DEPOSIT : April 25, 2005

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10, on the date indicated above, and is addressed to the MAIL STOP: PCT PATENT APPLICATION, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

  
Ingrid Mittendorf

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.:  CHUDоба, T. 1 PCT		SERIAL NO.: <b>10/532630</b>		
LIST OF REFERENCES CITED BY APPLICANT  (Use several sheets if necessary)				APPLICANT:				
				FILING DATE:		GROUP:		
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	5,051,594	09/1991	Fumihiko et al				
	AB	4,157,818	06/1979	Key				
	AC	3,201,980	08/1965	Webb				
	AD	5,343,748	09/1994	Keasey, et al.				
	AE	2,573,286	10/1951	Baker, et al.				
	AF							
	AG							
	AH							
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	WO 02 16907	02/2002	PCT				
	AM	WO 99 46576	09/1999	PCT				
	AN							
	AO							
	AP							
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AQ		"Microscratch and Load Relaxation Tests for Ultra-Thin Films" - Wu T. W. Journal of Materials Research, New York, NY, U.S., Vol. 6, no. 2, pages 407-426 February 1991					
	AR		International Search Report					
	AS							
EXAMINER					DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								